Abstracts

Time Domain Characterization of Coupled Interconnects and Discontinuities

---

J.-M. Jong, L.A. Hayden and V.K. Tripathi. "Time Domain Characterization of Coupled Interconnects and Discontinuities." 1994 MTT-S International Microwave Symposium Digest 94.2 (1994 Vol. II [MWSYM]): 1129-1132.

A time domain experimental technique for the characterization and modeling of general coupled interconnects and discontinuities is presented. The technique is based on a two-dimensional peeling algorithm and is validated by comparing the results obtained experimentally for the self and mutual equivalent circuit parameters with the theoretical predictions for a non symmetrical inhomogeneous coupled interconnect test structure.

❏ Return to main document.

Click on title for a complete paper.